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C. Amendments to the Claims.

1. (Currently Amended) A programmable logic device assembly, comprising:

a programmable logic circuit that provides functions according to configuration data including a self-test function; and

at least one nonvolatile store of the programmable logic device assembly coupled to the programmable logic circuit that provides self-test configuration data for the programmable logic circuit and ~~can~~ subsequently stores user configuration data.

2. (Currently Amended) The programmable logic device assembly of claim 1, wherein:

the programmable logic circuit ~~can~~ provides a self-test result when configured for self-test function.

3. (Original) The programmable logic device assembly of claim 2, further including:

a test port for providing the self-test result in a predetermined format.

4. (Original) The programmable logic device assembly of claim 1, wherein:

the at least one nonvolatile store includes a first nonvolatile store formed with the programmable logic circuit on a single integrated circuit die.

5. (Original) The programmable logic device assembly of claim 4, wherein: ·

the first nonvolatile store includes re-programmable nonvolatile circuit elements.

6. (Original) The programmable logic device assembly of claim 5, wherein:

the first nonvolatile store includes electrically erasable programmable read-only-memory cells.

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7. (Previously Presented) The programmable logic device assembly of claim 4, wherein:

> the self-test configuration data in the at least one nonvolatile store is set by at least one manufacturing process step for the programmable logic device assembly.

8. (Previously Presented) The programmable logic device assembly of claim 7, wherein:

> the at least one nonvolatile store includes a mask programmable read-only-memory that stores self-test configuration data and a separate nonvolatile memory that can store user configuration data.

9. (Original) The programmable logic device assembly of claim 1, wherein:

> the at least one nonvolatile store includes at least two sectors and self-test configuration data is stored in a first sector.

10. (Original) The programmable logic device assembly of claim 9, wherein:

> the first sector is a boot sector.

11. (Previously Presented) A method, comprising the steps of:

> performing a self-test on a programmable logic circuit of one package according to self-test configuration data in a self-test nonvolatile store of the one package; and
>
> storing user configuration data in a user nonvolatile store if the programmable logic circuit passes the self-test.

12. (Original) The method of claim 11, wherein:

> the self-test nonvolatile store is the same as the user nonvolatile store.

13. (Original) The method of claim 12, wherein:

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storing user configuration data includes programming user configuration data in locations that stored self-test configuration data.

14. (Previously Presented) The method of claim 12, wherein:

storing user configuration data includes storing user configuration data in locations that are different than those that store self-test configuration data.

15. (Previously Presented) The method of claim 11, further including:

forming the self-test nonvolatile store on the same die as the programmable logic circuit.

16. (Previously Presented) The method of claim 11, further including:

assembling the programmable logic circuit on one die with the nonvolatile store on another die into the one package.

17. (Original) The programmable logic circuit of claim 16, wherein:

the one package is a multi-chip module.

18. (Previously Presented) A programmable logic assembly self-test method, comprising the steps of:

storing self-test information in a first nonvolatile store of the assembly that places a programmable logic circuit of the assembly into a self-test configuration;

executing a self-test on the programmable logic circuit; and

providing user configuration information that places the programmable logic circuit in a user configuration.

19. (Original) The method of claim 18, wherein:

the user configuration data is stored in the first nonvolatile store.

20. (Original) The method of claim 18, wherein:

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the user configuration data is stored in a second nonvolatile store that
is different than the first nonvolatile store.

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